TÜVRheinland® Precisely Right. **Report #31363029.002** Rev. 0

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Electromagnetic Compatibility Test Report

Prepared in accordance with

EN 55022 Radiated Emissions

On

DC DC uModule Regulator LTM4624

Prepared for:

Linear Technology Corporation 1630 McCarthy Blvd. Milpitas, CA 95035 U.S.A.

Prepared by:

TUV Rheinland of North America, Inc. 1279 Quarry Lane, Ste. A Pleasanton, CA 94566 U.S.A.



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Revisions

Revision No.	Date	Reason for Change	Author
0	January 21, 2014	Original Document	N/A

Note: Latest revision report will replace all previous reports.



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	АТТ	TESTATION OI	F TEST	RESULTS		
Client:	Linear Technology Corporation 1630 McCarthy Blvd. Milpitas, CA 95035 U.S.A.			Richard Ying Tel. (408) 432-1900 Extension 3318 Rying@linear.com		
Model Name	LTM4624		Ser	al Number(s):	N/A (ENG.1)	
Model Number(s)	LTM4624			Date(s) Tested:	November 4, 2013	
Test Location(s):	TUV Rheinland of North America 2305 Mission College Blvd., Ste. 105 Santa Clara, CA 95054 U.S.A. Tel. (925) 249-9123					
Test Specifications:	Emissions: EN 55022:2010, CISPR 22:2008					
Test Result:	The abov	e product was found	d to be Co	mpliant to the	above test standard(s)	
Tested by: Gary Jorg	genson		Reviewed by: Conan Boyle			
Har	y Jorgens	~				
December 18, 2013 Date Na	me	Signature	January 21, 2014 Date Name Signature			
Other aspects:		Jignuure	Duit	Ivane	Signature	
		SANTA (CLARA			
FC				FRY CANAD	A	
US5251	Testin	g Cert #3331.02	2932D-1		1097 (A-0032)	



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1 General Information

1.1 Scope

This report is intended to document the status of conformance with the requirements of the listed standards based on the results of testing performed on November 4, 2013 on the DC DC uModule Regulator, Model No. LTM4624, manufactured by Linear Technology Corporation. This report only applies to the specific samples tested under the stated test conditions. It is the responsibility of the manufacturer to assure that additional production units of this model are manufactured with identical or EMI equivalent electrical and mechanical components. This report is further intended to document changes and modifications to the EUT throughout its life cycle. All documentation will be included as a supplement.

1.2 Purpose

Testing was performed to evaluate the EMC performance of the EUT (Equipment Under Test) in accordance with the applicable requirements, procedures, and criteria defined in the application of regulations and application of standards listed in this report.



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1.3 Sur	nmary of Test Results				
Applicant	Linear Technology Corporation	Tel.	(408) 432-1900 Extension 3318		
Applicant	1630 McCarthy Blvd. Milpitas, CA 95035	Contact	ct Richard Ying		
Description	DC DC uModule Regulator	E-mail Rying@linear.com			
Model Name	LTM4624	Input Power		4.0Vdc - 14Vdc	
Model Number(s)	LTM4624	Serial Number(s)		N/A (ENG.1)	
Test Date(s)	November 4, 2013	Test Engi	neer	Gary Jorgenson	

Standards	Description	Severity Level or Limit	Criteria	Test Result
EN 55022:2010, CISPR 22:2008 Product Family Standard Emissions	Information Technology Equipment – Radio Disturbance	See called out basic standards below	See Below	Complies
EN 55022:2010, CISPR 22:2008	Radiated Emissions	Class B, 30 - 1000 MHz	Limit	Complies



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2 Laboratory Information

2.1 Accreditations & Endorsements

2.1.1 US Federal Communications Commission

FC TUV Rheinland of North America EMC test facilities located at 1279 Quarry Lane, Ste. A, Pleasanton, CA, 94566, and 2305 Mission College Blvd, Ste. 105, Santa Clara, CA 95054, are recognized by the Commission for performing testing services for the general public on a fee basis. These laboratory test facilities have been fully described in reports submitted to and accepted by the FCC (Pleasanton Registration No. US5254, Santa Clara Registration No. US5251). The laboratory Scopes of Accreditation include Title 47 CFR Parts 15, 18 and 90. The accreditations are updated every three years.

2.1.2 A2LA



TUV Rheinland of North America EMC test facilities are accredited by the American Association for Laboratory Accreditation (A2LA). The laboratories have been assessed and accredited by A2LA in accordance with ISO Standard 17025:2005 (Testing Certificate #3331.02). The Scope of Laboratory Accreditation includes emission and immunity testing. The accreditations are

updated annually.

2.1.3 Industry Canada

Industry Canada Industrio Concentrio Conc

based on the test procedures described in ANSI C63.4-2009. The Santa Clara 10-meter Semi-Anechoic Chamber, Registration No. 2932D-1, has been accepted by Industry Canada to perform testing to 3 and 10 meters based on the test procedures described in ANSI C63.4-2009.

2.1.4 Japan – VCCI



The Voluntary Control Council for Interference by Information Technology Equipment (VCCI) is a group that consists of Information Technology Equipment (ITE) manufacturers and EMC test laboratories. The purpose of the Council is to take voluntary control measures against electromagnetic interference from Information Technology

Equipment, and thereby contribute to the development of a socially beneficial and responsible state of affairs in the realm of Information Technology Equipment in Japan. TUV Rheinland of North America EMC test facilities located at 1279 Quarry Lane, Ste. A, Pleasanton, CA, 94566, and 2305 Mission College Blvd, Ste. 105, Santa Clara, CA 95054, have been assessed and approved in accordance with the Regulations for Voluntary Control Measures.

VCCI Registration No. for Pleasanton: A-0031

VCCI Registration No. for Santa Clara: A-0032



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2.2 Test Facilities and EMC Software

Test facilities are located at 1279 Quarry Lane, Ste. A, Pleasanton, California 94566, U.S.A. and 2305 Mission College Blvd., Ste. 105, Santa Clara, 95054, U.S.A. (Santa Clara is the Pleasanton Annex).

2.2.1 Emission Test Facility

The Semi-Anechoic Chambers and AC Line Conducted measurement facilities used to collect radiated and conducted emissions data have been constructed in accordance with ANSI C63.7:1992. The Santa Clara 10 meter semi-anechoic chamber has been measured in accordance with and verified to comply with the theoretical volumetric normalized site attenuation of ANSI C63.4:2009 and SVSWR requirements of CISPR 16-1-4 Consol. Ed. 3.0 (2010-04), at test distances of 3 and 10 meters. This site has been described in reports dated November 1st, 2006, submitted to the FCC, and accepted by letter dated November 28, 2006. The site is listed with the FCC and accredited by A2LA (Testing Certificate #3331.02). The Pleasanton 5 meter semi-anechoic chamber has been verified to comply with the theoretical volumetric normalized site attenuation of ANSI C63.4:2009 and SVSWR requirements of CISPR 16-1-4 Consol. Ed. 3.0 (2010-04) at a test distance of 3 meters. This site has been described in reports dated November 1 st, 2006, and SVSWR requirements of CISPR 16-1-4 Consol. Ed. 3.0 (2010-04) at a test distance of 3 meters. This site has been described in reports dated November 1 st, 2006, submitted to the FCC, and accepted by letter dated November 28, 2006. The site is listed with the FCC and accepted by letter dated November 28, 2006. The site is listed to the FCC, and accepted by letter dated November 28, 2006. The site is listed with the FCC and accredited by A2LA (Testing Certificate #3331.02).

2.2.2 Immunity Test Facility

ESD, EFT, Surge, PQF: These tests are performed in an environmentally controlled room with a 3.7 m x 3.7 m x 3.175 mm thick aluminum floor connected to PE ground. For ESD testing, tabletop equipment is placed on an insulated mat with a surface resistivity of 10^9 Ohms/square on a 1.6 m x 0.8 m x 0.8 m high non-conductive table with a 3.175 mm aluminum top (Horizontal Coupling Plane). The HCP is connected to the main ground plane via a low impedance ground strap through two 470 k Ω resistors. The Vertical Coupling Plane consists of an aluminum plate 50 cm x 50 cm x 3.175 mm thick. The VCP is connected to the main ground plane via a low impedance ground strap through two 470 k Ω resistors. For each of the other tests, the HCP is removed.

RF Field Immunity testing is performed in a 10m semi-anechoic chamber with absorber added to floor.

RF Conducted and Magnetic Field Immunity testing is performed on a 4.9 m x 3.7 m x 3.175 mm thick aluminum ground plane which is connected to one end of the anechoic chamber.

All test areas allow a minimum distance of 1 meter from the EUT to walls or conducting objects.

Manufacturer	Name	Version	Test Type				
Hewlett-Packard	HP85876B	A.01.00 970825	Radiated & Conducted Emissions				
EMISoft	Vasona	5.0	Radiated & Conducted Emissions				
ETS-Lindgren	TILE	4.2.A	Radiated Emissions > 1 GHz				
ETS-Lindgren	TILE	V.3.4.K.22	Radiated & Conducted Immunity				

2.2.3 EMC Software - Santa Clara



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Manufacturer	Name	Version	Test Type
Haefely	WinFEAT	1.6.3	Surge
Thermo Electron - Keytek	CEWare32	3.0	EFT/Surge/Voltage Dips & Interrupt
Voltech	IEC61000-3	1.15.07RC	Harmonic & Flicker

2.2.4 EMC Software - Pleasanton

Manufacturer	Name	Version	Test Type
ETS-Lindgren	TILE	3.4.K.14 @ 4.0.A.5	Radiated & Conducted Emissions
EMISoft	Vasona	5.0	Radiated & Conducted Emissions
Agilent	Agilent MXE	A.11.02	Radiated & Conducted Emissions
ETS-Lindgren	TILE	3.4.K.14	Radiated & Conducted Immunity
Thermo Electron - Keytek	CEWare32	4.00	EFT/Surge/Voltage Dips & Interrupt
Voltech	IEC61000-3	1.21.07RC2	Harmonic & Flicker



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2.3 Measurement Uncertainty

Two types of measurement uncertainty are expressed in this report, per *ISO Guide To The Expression Of Uncertainty In Measurement*, 1st Edition, 1995.

The Combined Standard Uncertainty is the standard uncertainty of the result of a measurement when that result is obtained from the values of a number of other quantities, equal to the positive square root of a sum of terms, the terms being the variances or co-variances of these other quantities weighted according to how the measurement result varies with changes in these quantities. The term standard uncertainty is the result of a measurement expressed as a standard deviation.

The Expanded Uncertainty defines an interval about the result of a measurement that may be expected to encompass a large fraction of the distribution of values that could reasonably be attributed to the measurand. The fraction may be viewed as the coverage probability or level of confidence of the interval.

2.3.1 Sample Calculation – radiated & conducted emissions

The field strength is calculated by subtracting the Amplifier Gain and adding the Cable Loss and Antenna Correction Factor to the measured reading. The basic equation is as follows:

Field Strength $(dB\mu V/m) = RAW - AMP + CBL + ACF$

Where: RAW = Measured level before correction ($dB\mu V$)

AMP = Amplifier Gain (dB)

CBL = Cable Loss (dB)

ACF = Antenna Correction Factor (dB/m)

$$\mu V/m = 10^{\frac{dB\mu V/m}{20}}$$

Sample radiated emissions calculation @ 30 MHz

Measurement +Antenna Factor-Amplifier Gain+Cable loss=Radiated Emissions (dBuV/m)

25 dBuV/m + 17.5 dB - 20 dB + 1.0 dB = 23.5 dBuV/m



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2.3.2 Measurement Uncertainty Emissions

Per CISPR 16-4-2	$\mathbf{U}_{\mathbf{lab}}$	Ucispr			
Radiated Disturbance @ 10 r	neters				
30 – 1,000 MHz	2.25 dB 4.51 dB				
Radiated Disturbance @ 3 meters					
30 – 1,000 MHz	2.26 dB 4.52 dB				

The expanded uncertainty at a level of 95% confidence is obtained by multiplying the combined standard uncertainty by a coverage factor of 2. Compliance criteria are not based on measurement uncertainty.

2.4 Calibration Traceability

All measurement instrumentation is traceable to the National Institute of Standards and Technology (NIST). Measurement method complies with ANSI/NCSL Z540-1-1994 and ISO Standard 17025:2005. Equipment calibration records are kept on file at the test facility.

2.5	Measurement Equipment Used
-----	----------------------------

Equipment	Manufacturer	Model #	Serial/Inst #	Last Cal mm/dd/yy	Next Cal mm/dd/yy	Test
EMI Receiver	Agilent	MXE	MY51210195	1/19/2013	1/19/2014	RE
100 kHz – 1 GHz Preamplifier	HP	8447D	2944A07486	1/17/2013	1/17/2014	RE
Bilog Antenna Emissions	Sunol Sciences	JB3	A020502	04/12/2013	04/12/2015	RE

Note: CE=Conducted Emissions, CI=Conducted Immunity, DP=Disturbance Power, EFT=Electrical Fast Transients, ESD=Electrostatic Discharge, FLI=Flicker, HAR=Harmonics, MF=Magnetic Field Immunity, NCR=No Calibration Required, RE=Radiated Emissions, RI=Radiated Immunity, SI=Surge Immunity, VDSI=Voltage Dips and Short Interruptions



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3 Product Information

3.1 Product Description

See Section 5.4.

3.2 Equipment Modifications

Added 47uF capacitor to input.

3.3 Test Plan

The EUT product information, test configuration, mode of operation, test types, test procedures, test levels, pass/failure criteria, in this report were carried out per the product test plan located in Appendix A of this report.



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Figure 1 - External Photo of EUT





Figure 2 - Photo of EUT Demo Board



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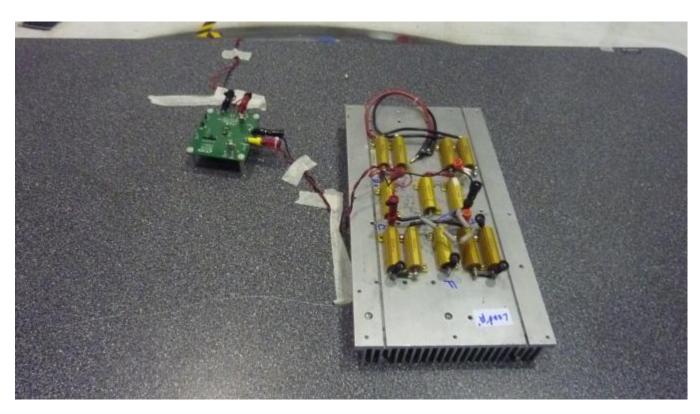


Figure 3 - Photo of EUT Load



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4 Emissions

4.1 Radiated Emissions

This test measures the electromagnetic levels of spurious signals generated by the EUT that radiated from the EUT and may affect the performance of other nearby electronic equipment.

Results	Complies (as tested per this report)			Test	Test Date(s)		November 4	, 2013
Standard	EN 55022:2010, CI	SPR 22:2	008					
Model Number	LTM4624			Seria	1#	N/A	(ENG.1)	
Configuration	See test plan for det	ails.						
Test Setup	Tested in the 10-me	ter chamb	ber, place	d on turnt	ble:	see tes	t plan for deta	uls.
EUT Powered By	DC Power supply							
Environmental Conditions	November 4, 2013	November 4, 2013 Temp 21° C Humidity 42% Pressure 1017 mbar					1017 mbar	
Frequency Range	30 - 1000 MHz							
Perf. Criteria	Class B Perf. Verification Readings Under Limit							
Mod. to EUT	Added 47uf cap to in	nput	Test Pe	rformed]	By	Gary	Jorgenson	

4.1.1 Overview of Test

4.1.2 Test Procedure

Radiated emissions tests were performed using the procedures of ANSI C63.4:2009 including methods for signal maximizations and EUT configuration. The photos included with the report show the EUT in its maximized configuration.

The frequency range from 30 - 1000 MHz was investigated for radiated emissions.

4.1.3 Deviations

There were no deviations from the test methodology listed in the test plan for the radiated emission test.

4.1.4 Final Test

All final radiated emissions measurements were below the specification limits.

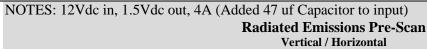


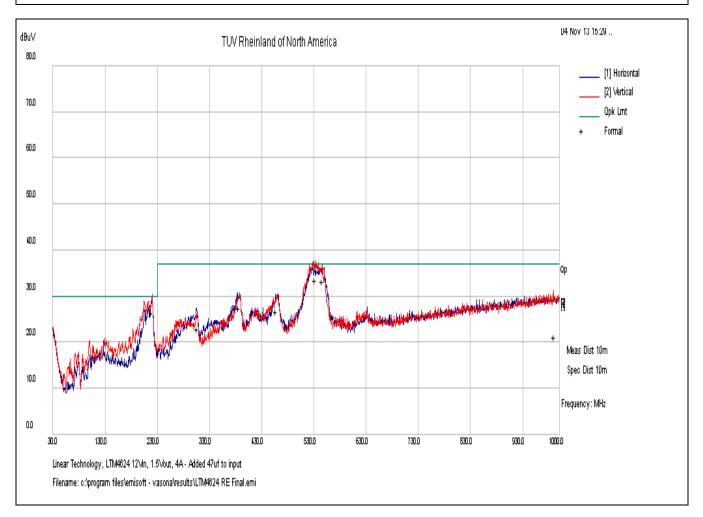
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4.1.5 Plots







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4.1.6 Final Peak Data – 30 - 1000 MHz

Frequency MHz	Raw dBuV	Cable Loss	AF dB	Level dBuV	Measurement Type	Pol	Hgt cm	Azt Deg	QP Limit dBuV	Margin dB
532.5813	44.36	3.39	-10.09	37.65	Peak [Scan]	V	100	74	37	0.65
220.3625	44.06	2.45	-16.16	30.35	Peak [Scan]	V	100	190	30	0.35
989.0875	30.68	4.35	-3.92	31.11	Peak [Scan]	V	100	218	37	-5.89
387.6875	39.98	3	-12.28	30.7	Peak [Scan]	Н	200	236	37	-6.3
456.8	38.22	3.19	-10.92	30.49	Peak [Scan]	Н	200	291	37	-6.51
557.4375	36.8	3.45	-9.84	30.42	Peak [Scan]	Н	200	320	37	-6.58
30.60625	28.84	1.47	-7.11	23.21	Peak [Scan]	V	100	93	30	-6.79
304.6313	37.99	2.76	-13.27	27.47	Peak [Scan]	Н	400	264	37	-9.53
79.10625	35.9	1.81	-19.96	17.75	Peak [Scan]	V	400	68	30	-12.25

4.1.7 Final Quasi Peak Data – 30 - 1000 MHz

Frequency MHz	Raw dBuV	Cable Loss	AF dB	Level dBuV	Measurement Type	Pol	Hgt cm	Azt Deg	QP Limit dBuV	Margin dB
532.7156	40.13	3.39	-10.09	33.43	Quasi Peak	V	101	74	37	-3.57
219.1806	40.17	2.45	-16.19	26.43	Quasi Peak	V	104	213	30	-3.57
989.8775	20.57	4.35	-3.9	21.02	Quasi Peak	V	116	212	37	-15.98
386.2331	36.61	2.99	-12.3	27.3	Quasi Peak	н	230	248	37	-9.7
457.0106	34.26	3.19	-10.91	26.53	Quasi Peak	н	188	290	37	-10.47
545.4984	39.81	3.41	-9.95	33.27	Quasi Peak	н	176	315	37	-3.74
306.3956	33.43	2.76	-13.21	22.98	Quasi Peak	н	323	259	37	-14.02

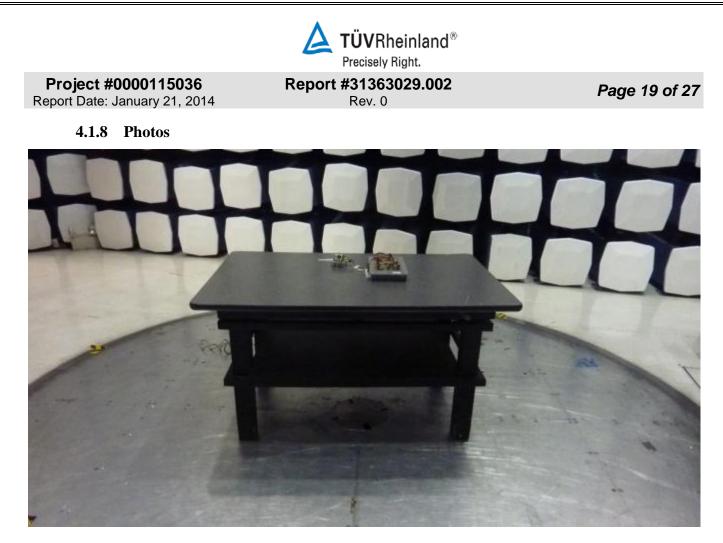


Figure 4 - Radiated Emissions Test Setup 30 - 1000 MHz - Front



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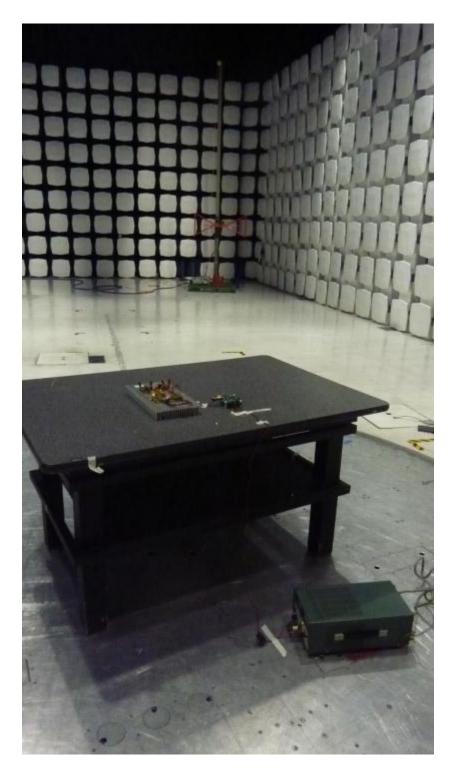


Figure 5 - Radiated Emissions Test Setup 30 - 1000 MHz - Back



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Appendix A

5 Test Plan

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This test report is intended to follow this test plan outlined here in unless otherwise stated in this here report. The following test plan will give details on product information, standards to be used, test set ups and refer to TUV test procedures. The test procedures will give the steps to be taken when performing the stated test. The product information below came via client, product manual, product itself and or the internet.

5.1 General Information

Client	Linear Technology Corporation			
	1630 McCarthy Blvd.			
Address 1	Milpitas, CA 95035			
Contact Person	Richard Ying			
Telephone	(408) 432-1900 Extension 3318			
e-mail	Rying@linear.com			

5.2 EUT Designation

Model Name	LTM4624
Model Number(s)	LTM4624

5.3 EUT Description

DC DC uModule Regulator



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5.4 Equipment Under Test (EUT) Description

The LTM®4624 is a complete 4A step-down switching mode uModule® regulator in a tiny 6.25mm×6.25mm×5.01mm BGA package. The LTM4624 operates from a 4V to 14V input supply, delivering a regulated output adjustable between 0.6V to 5.5V, ideal for applications in communications, storage, industrial and medical systems.

5.5 **Product Environment**

\boxtimes	Residential	Hospital
\boxtimes	Light Industrial	Small Clinic
\boxtimes	Industrial	Doctor's office
	Other	

*Check all that apply

5.6 Countries

\boxtimes	USA
\boxtimes	Europe

*Check all that apply



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5.7 Applicable Documents

Standards	Description
EN 55022:2010, CISPR 22:2008 Standard Emissions	Information Technology Equipment – Radio Disturbance
EN 55022:2010, CISPR 22:2008	Radiated Emissions



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5.8 EUT Electrical Power Information

Nomo	# of	Trino	Output	Voltage	AC Valtaga	Current	
Name	Phases	Phases Type		Max	Voltage Frequency	Max.	
DC Input	$\begin{array}{c}1 \ \square \\3 \ \square \\\text{None} \ \blacksquare\end{array}$	AC □ DC ⊠ Host □ Batteries □	4.0 V	14 V	1 MHz	Load Dependent	
DC Output	$\begin{array}{c}1 \ \square \\3 \ \square \\\text{None} \ \blacksquare\end{array}$	AC □ DC ⊠ Host □ Batteries □	0.6 V	5.5 V	1 MHz	4 A Max	

Notes

5.9 EUT Clock/Oscillator Frequencies

Reference Designation	Speed (MHz)	Туре
		□ Oscillator □ Microprocessor

5.9.1 Radiated Emissions, Upper Frequency

\boxtimes	Less than 108 MHz	Scan to 1 GHz				
	Less than 500 MHz	Scan to 2 GHz				
	Less than 1000 MHz	Scan to 5 GHz				
	Greater than 1000 MHz	Scan to 5 th Harmonic or 40 GHz (whichever is lower)				



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5.10 Electrical Support Equipment

Reference Designation	Manufacturer	Model	Serial Number	BSMI #
Power Supply	Kikusui	PAD 16-30L		N/A
Load Resistors	N/A	N/A		N/A

5.11 Non - Electrical Support Equipment

Reference Designation	Manufacturer	Model	Serial Number or Description (e.g., Type of Gas or Liquid)
None			

5.12 EUT Equipment/Cabling Information

	Connected To	Cable Type					
EUT Port		Length (Meters)			Bead Yes / No		
VIN	Power Supply	1 meter		\boxtimes		\boxtimes	
VOUT	Resistive Load	0.2 meters		\boxtimes		\boxtimes	

5.13 EUT Test Program

None

5.14 EUT Modes of Operation

• 12 V Input, 1.5 V Output @ 4 A

5.15 Monitoring of EUT during Testing

For Emissions testing the EUT output voltage is checked during the test.



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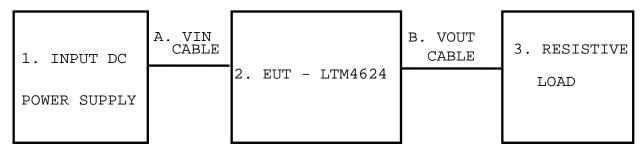
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5.16 EUT Configuration

5.16.1 Description

Configuration		Description				
One Only		LTM4624 installed on demo board DC1889A				
Notes	Notes All configurations tested with a resistive load					

5.16.2 Block Diagram





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5.17 Emissions

5.17.1 Radiated Emissions

5.17.1.1 Preliminary Radiated Emissions Test Setup

Standard	EN 55022:2010, CISPR 22:2008		TUV Te	st Procedure	MS-0005192			
Limit	Class B	Emissions Ve	erification	Emissions	Emissions Under Limit			
Frequency Range	30 - 1000 MHz							
Scan #1	Pre-scan 30 – 1000 MHz	Antenna Distance	10m	Detector	Peak			
Configuration	See Section 5.16							
Notes	None							

5.17.1.2 Final Radiated Emissions Test Setup

Standard	EN 55022:2010, CISPR 22:2008		TUV Test Procedure			MS-0005192	
Limit	Class B	Emissions Verification		Emi	Emissions Under Limit		
Frequency Range	30 - 1000 MHz						
Scan #1	Final Scan 30 – 1000 MHz 12 V Input, 1.5 V Output @ 4 A		ntenna istance	10m	Om Detector		Quasi Peak
Configuration	ation See Section: 5.16						
Notes	None						

END OF REPORT